

pureCOLD
fast electronics for
 β - α pile-up suppression
first on-line measurements

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Peter Rasmussen

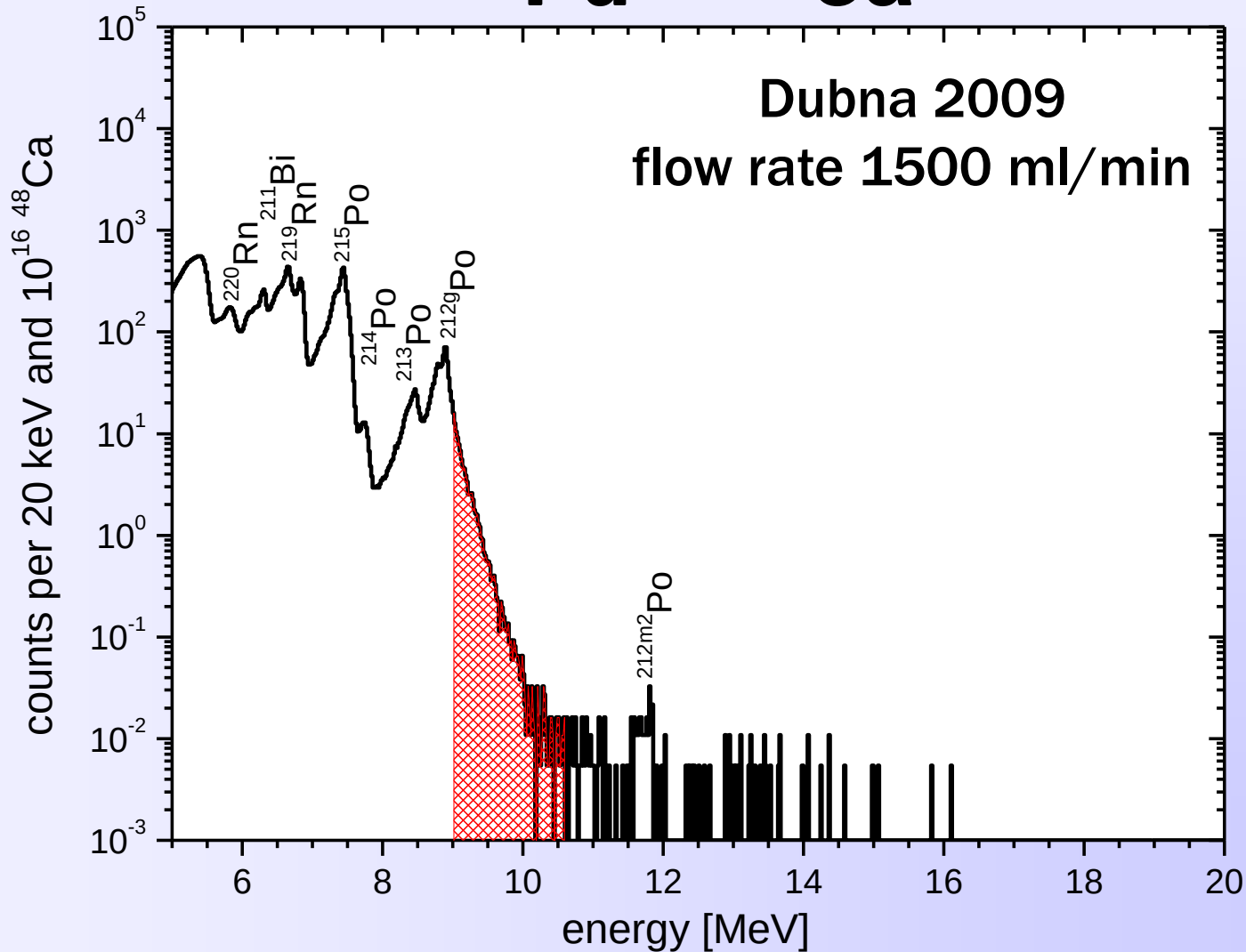
Pile-Up Rejection Electronics for Cryo On-Line Detector pureCOLD

Outline

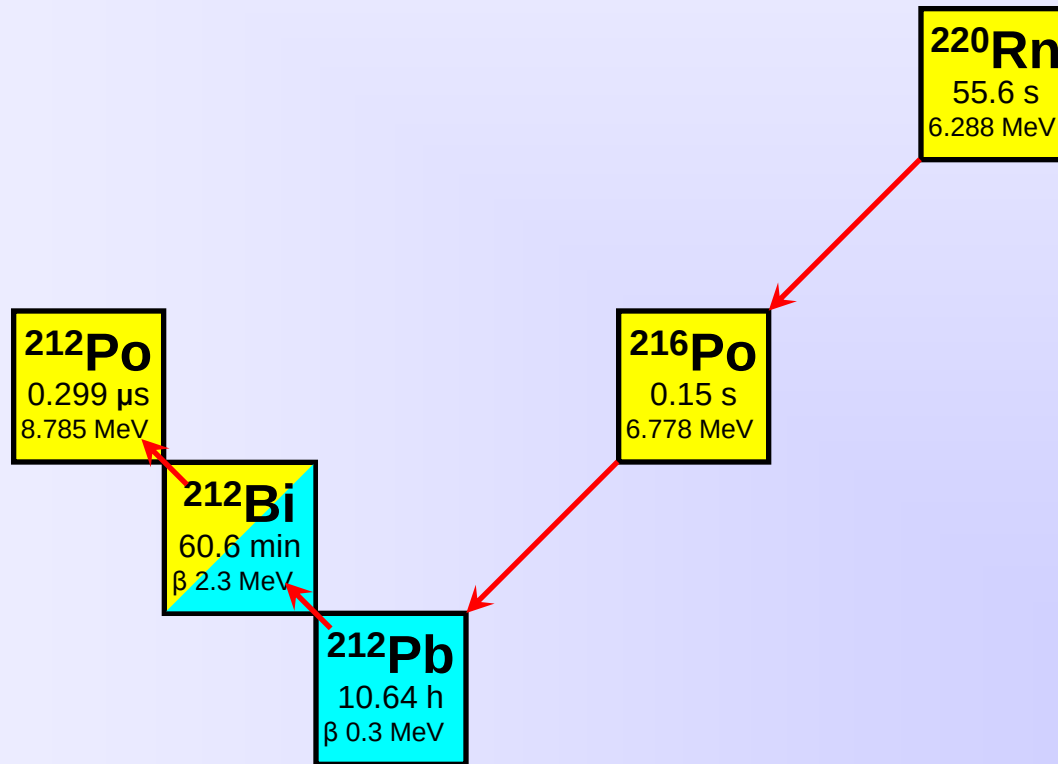
- **Introduction**
- **Final hardware design**
- **Measurements PSI & Dubna 2011**
- **Summary & Outlook**

α -Spectrum

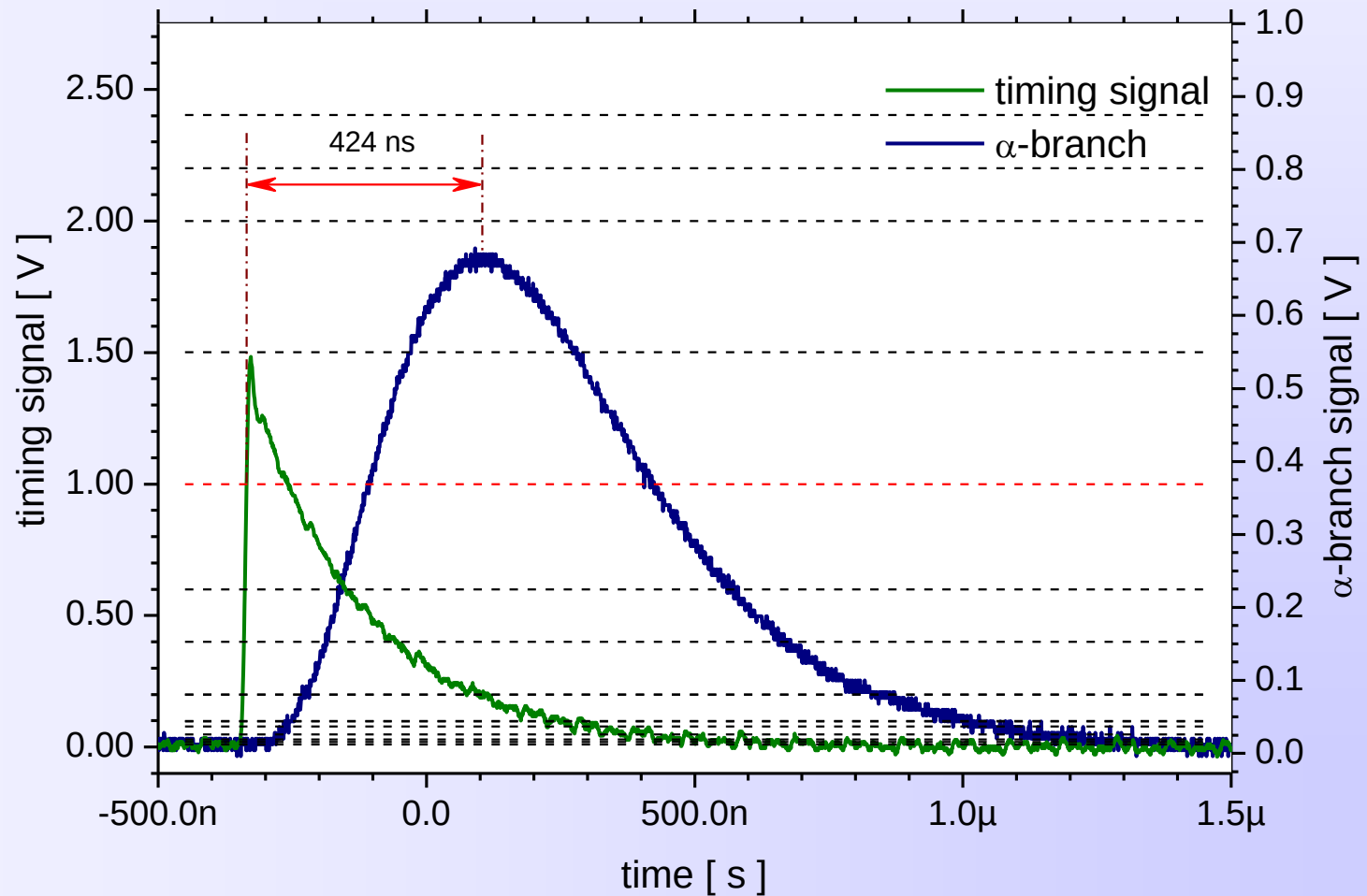
$^{242}\text{Pu} + ^{48}\text{Ca}$



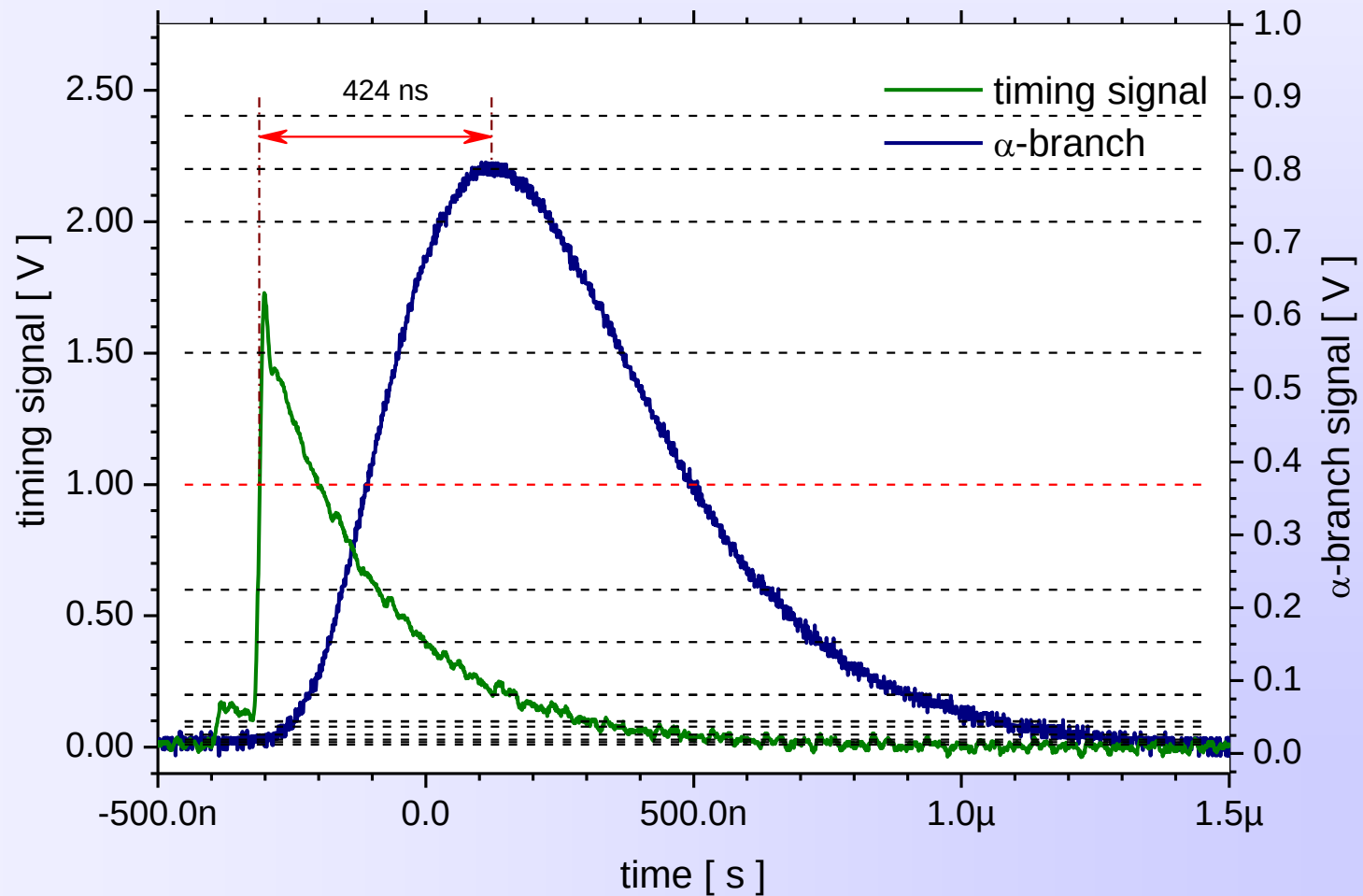
β - α Pile-Up Problem



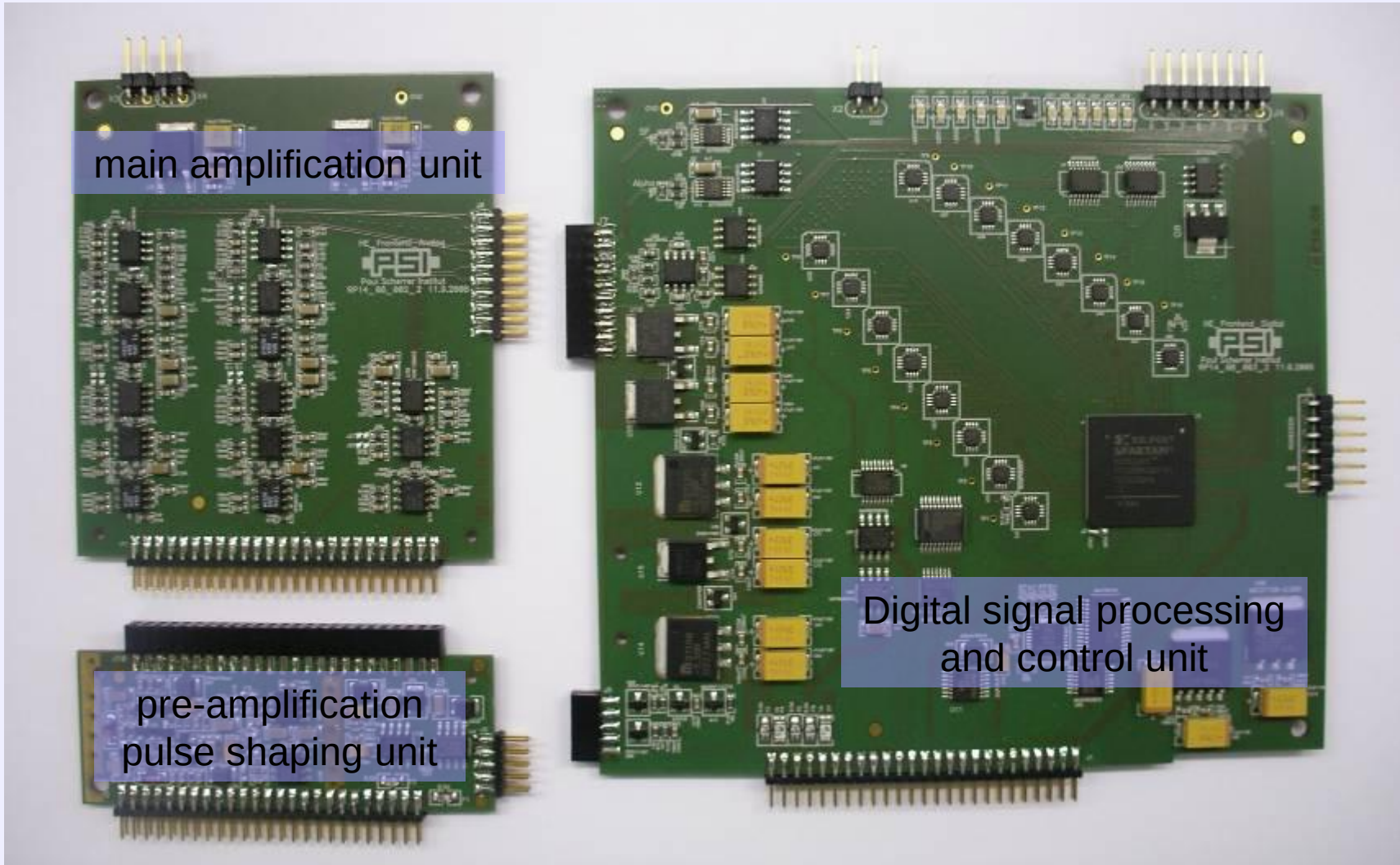
Working Principle pure α -Event



Working Principle β - α Pile-Up Event

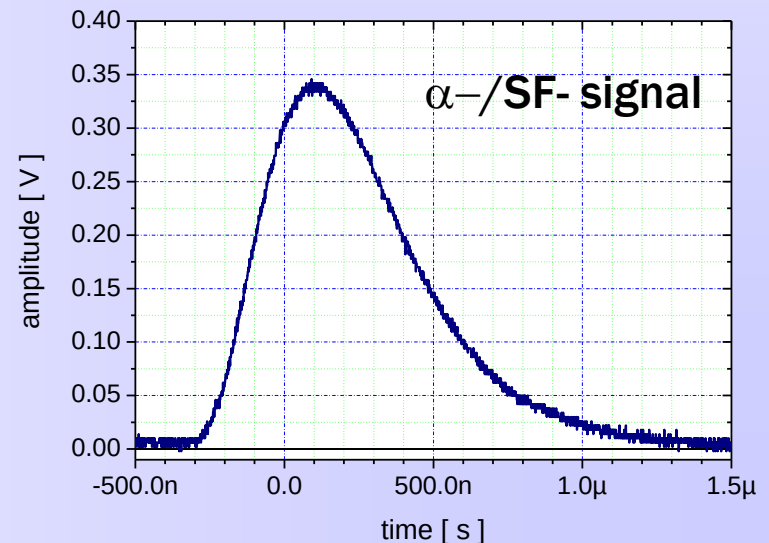
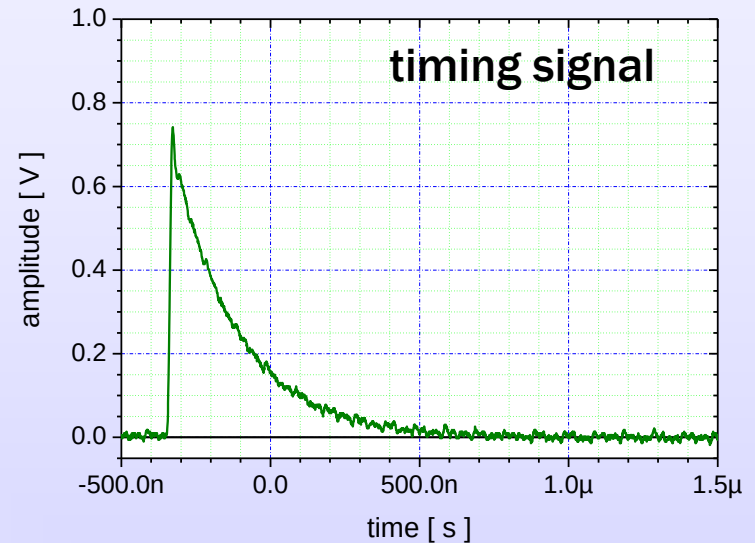


Frontend PCB Design



Preamplifier / Shaper / Amplifier

- pre-amplifier
 - *gain $\times 10$*
 - *shaping time 220 ns*
- main amplifier
 - *separate α - and SF-branch*
 - *fixed gain full range*
 α : 7.5MeV, 15MeV, 30MeV
SF: 75MeV, 150MeV, 300MeV
 - *fast timing amplifier*
 - *fixed gain full range*
1.5 MeV, 4.5 MeV, 7.5 MeV
- signal width
 - *375 ns timing signal*
 - *650 ns spectroscopic signal*



Comparator / ADC / FPGA

■ 16 × fast comparators

- 150 ps switching time
10 ps time jitter
- run-time matching via
cable delay better 0.7 ps
- levels adjustable via DAC

■ 8 phase clock

- 4 × 250 MHz DDR clock
- run-time matching via
cable delay better 0.3 ps
- time resolution 0.5 ns

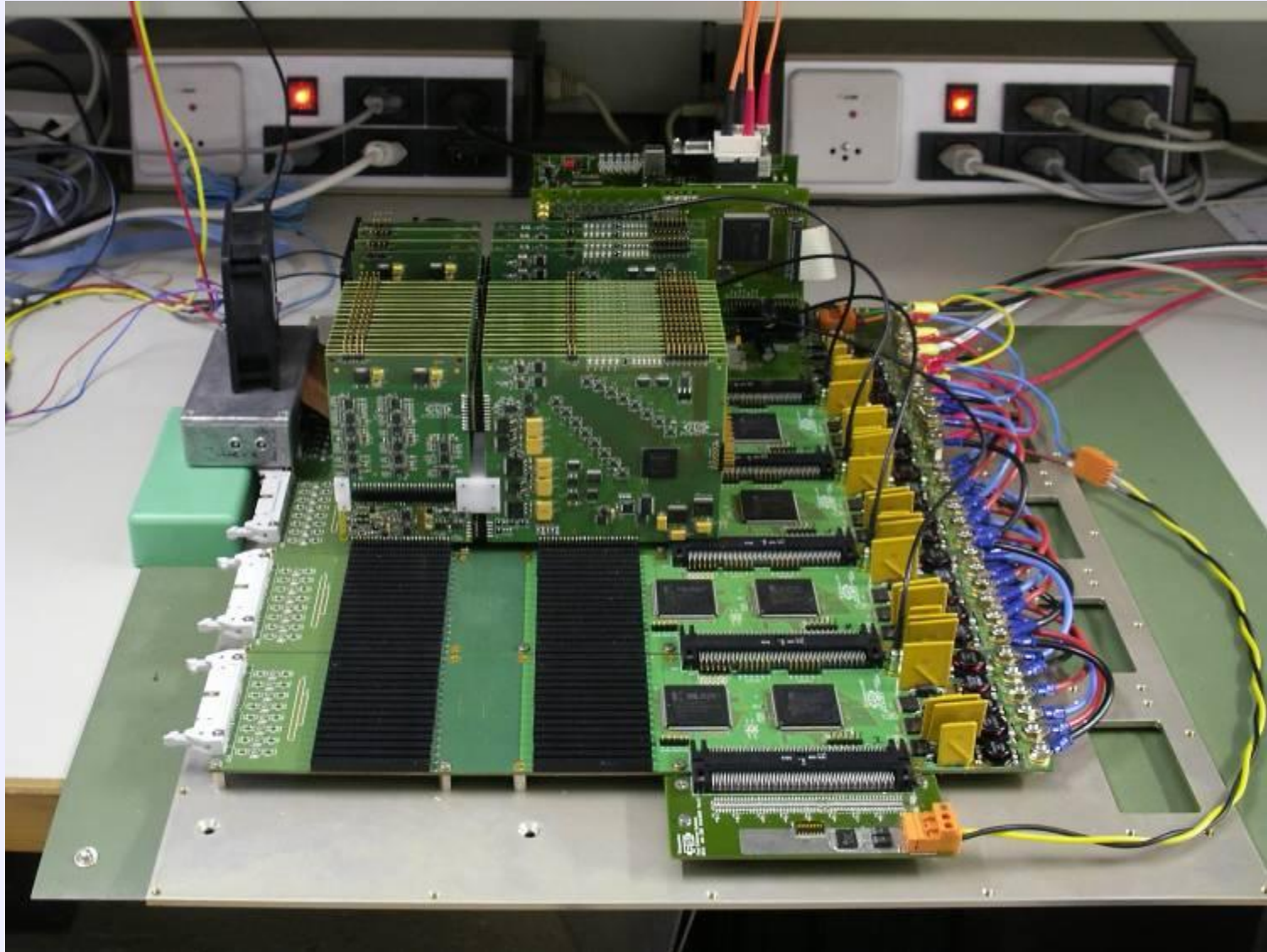
■ 2 × ADC 500 kSamples/s

- 16 bit conversion depth
- 2.5 V bipolar range
- FPGA controlled conversion
- serial data connection

■ Spartan 3 FPGA

- 16 × counters for fast
comparator time-stamps
- 2 × ADC readout
- 340 Event FIFO
- 7x free programmable
interconnection signals

PCB Interconnection Design



PCB & PC Interconnection

■ Main-board

- *16 × front end PCBs*
- *Spartan 3 FPGA*
- *independent read-out for each FE channel*
- *20 Event FIFO for each FE*
- *multiplexed test pulse input*
- *5x free programmable interconnection signals*

■ DAC test pulse generator

- *Fujitsu MB86064 DAC*
14-bit; 800 MSamples/s
- *2 × free programmable waveforms up to 20.48 μs*
- *adjustable reference voltage via 8 bit DAC*

■ Interface to PC

- *Inova GigaSTaR*
- *point to point bi-directional fiber optics connection*
- *400 MBit/sec*
10 MHz system clock
- *max. through put*
574 kEvents/sec
- *to PC 32 bit data width*
- *4096 Event FIFO at PC*
- *from PC 8 bit data width*
- *Serial interface MCU to PC*
- *serial ports RS-232 via copper, fiber optics or USB 1.1*

Performance Numbers

■ ADC

- *120 ns conversion time*
- *1.8 μ s transfer to FPGA*
- *3.1 μ s transfer to FIFO*

■ Interconnection FE to MB

- *serial data bus*
- *all FEs parallel processed*
- *107 μ s transfer time*
or ~9.4 kEvents/sec

■ Transfer MB to GigaSTaR

- *32 bit parallel data bus*
- *1 μ s polling over MBs*
- *12 μ s transfer time*
or 83.3 kEvents/sec

■ GigaSTaR to PC

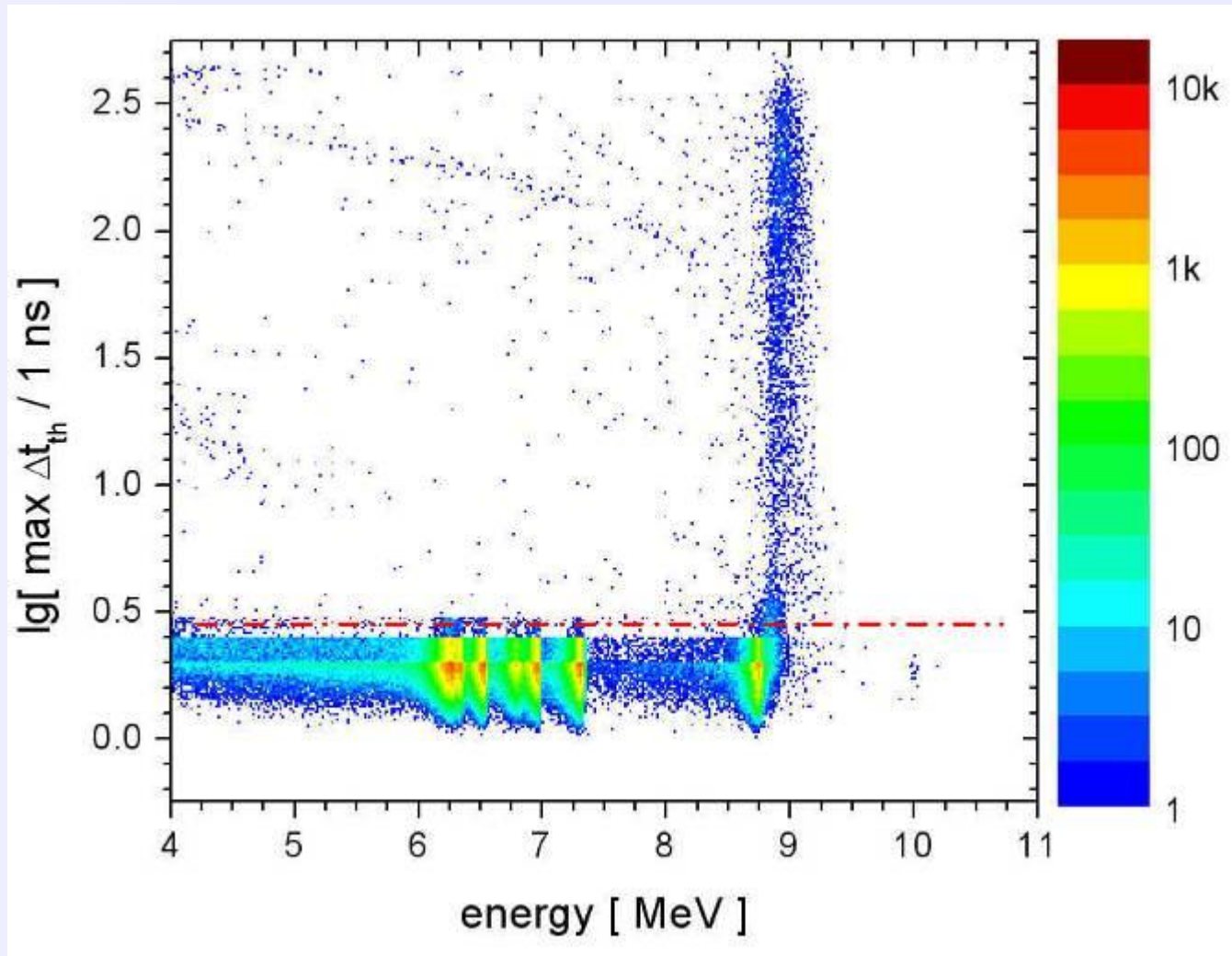
- *400 MBit/sec*
10 MHz system clock
- *max. through put*
574 kEvents/sec

■ Experimental Event rate for 1 channel

- *simulated α -events*
- *4 μ s time between consecutive events*
- *peak rate 9.0 kEvents/sec*

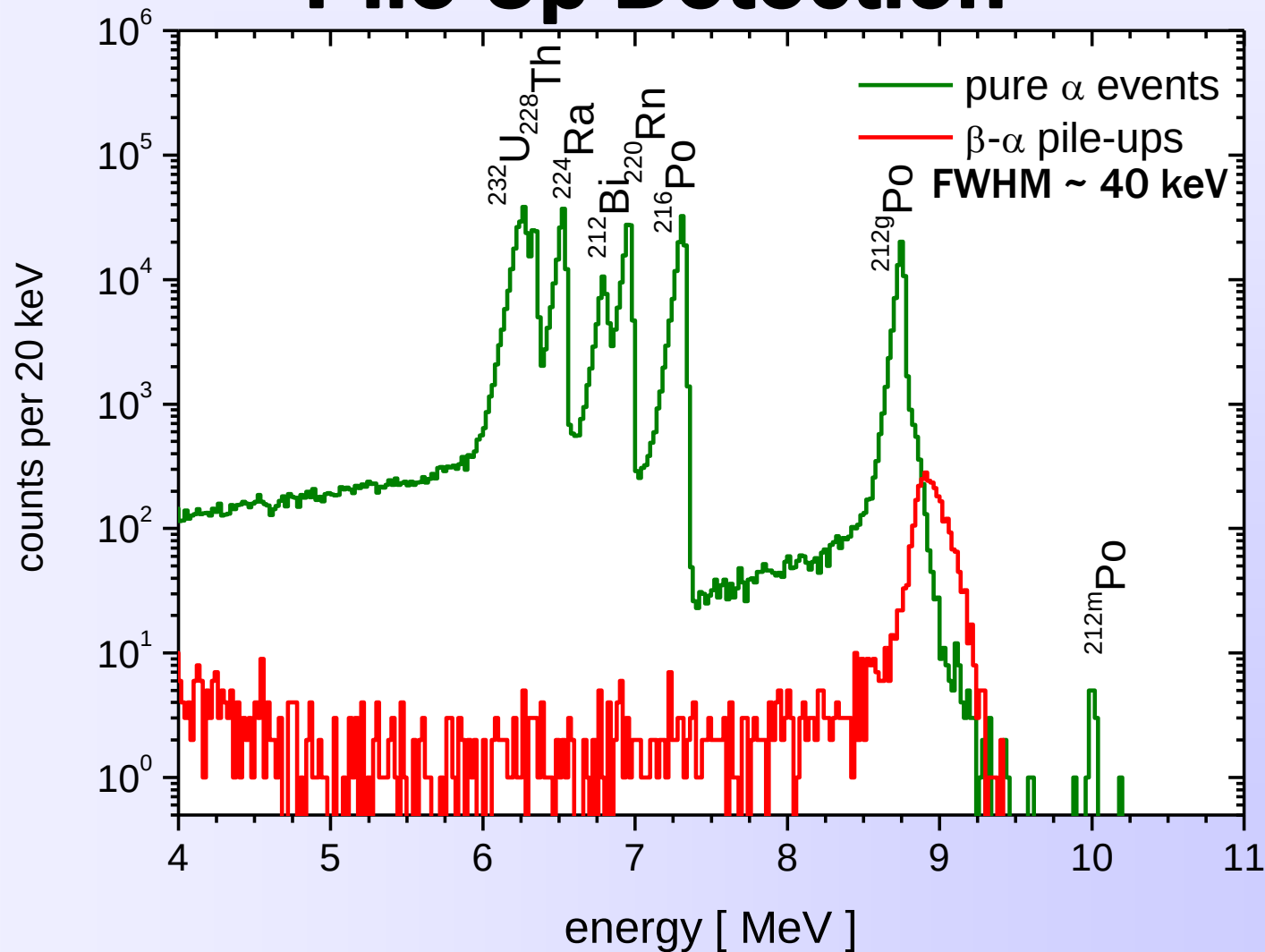
^{232}U Test Experiments

Threshold-Time vs. α -Energy



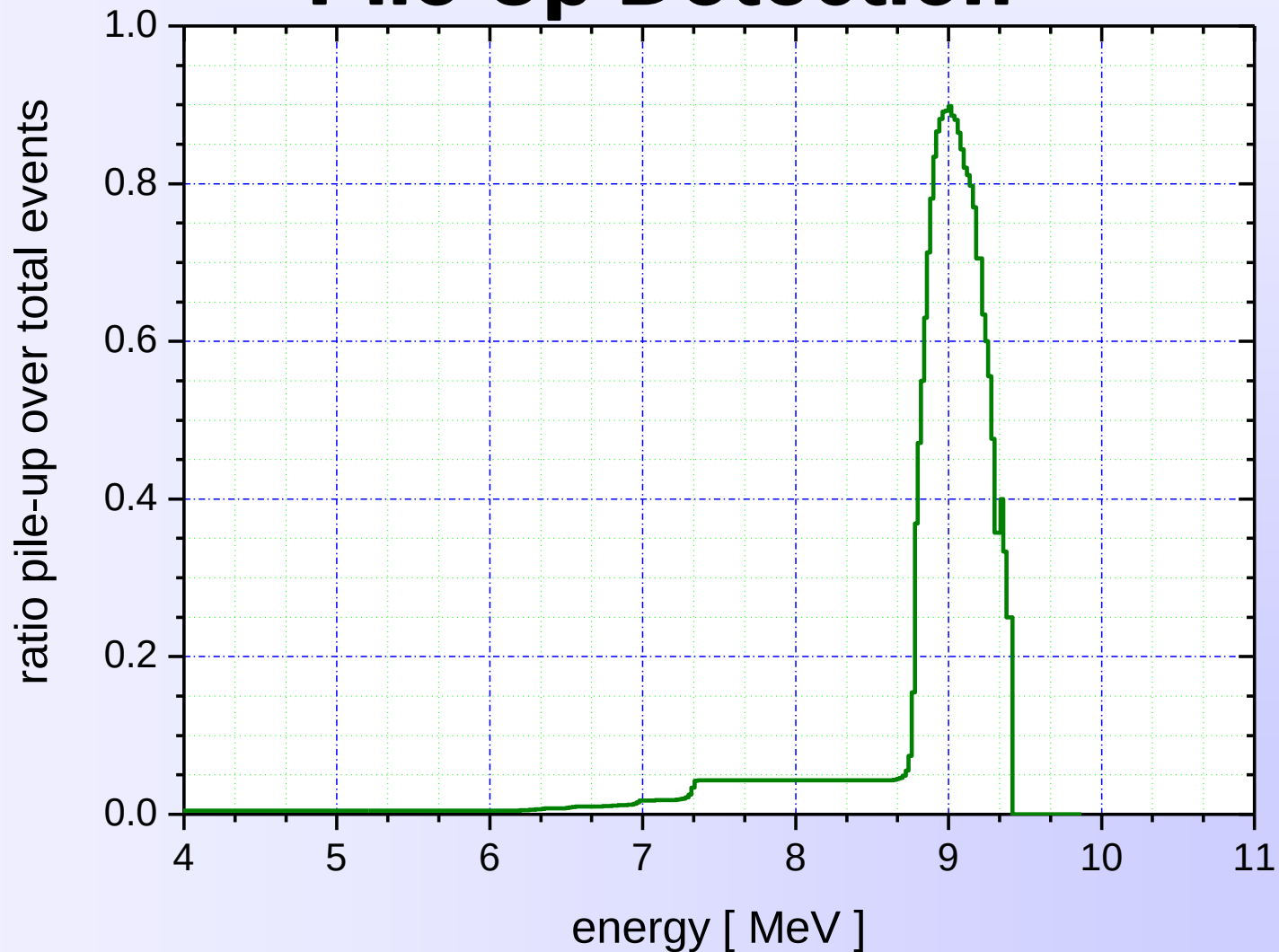
^{232}U Test Experiments

Pile-Up Detection

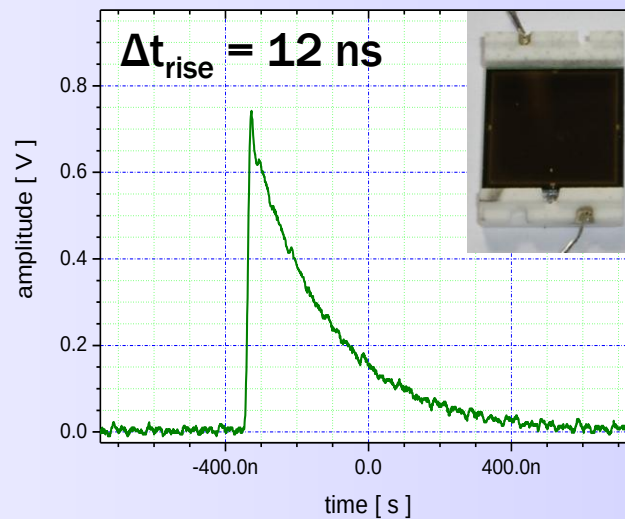
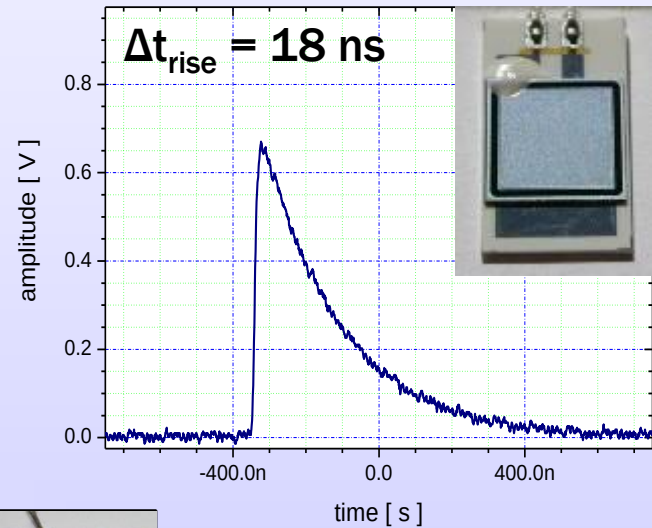
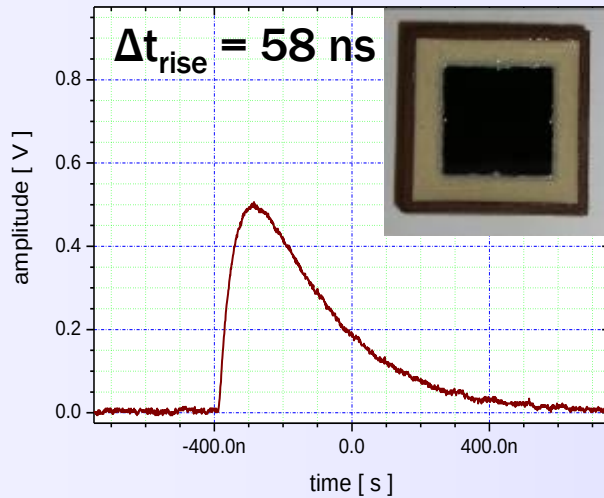


^{232}U Test Experiments

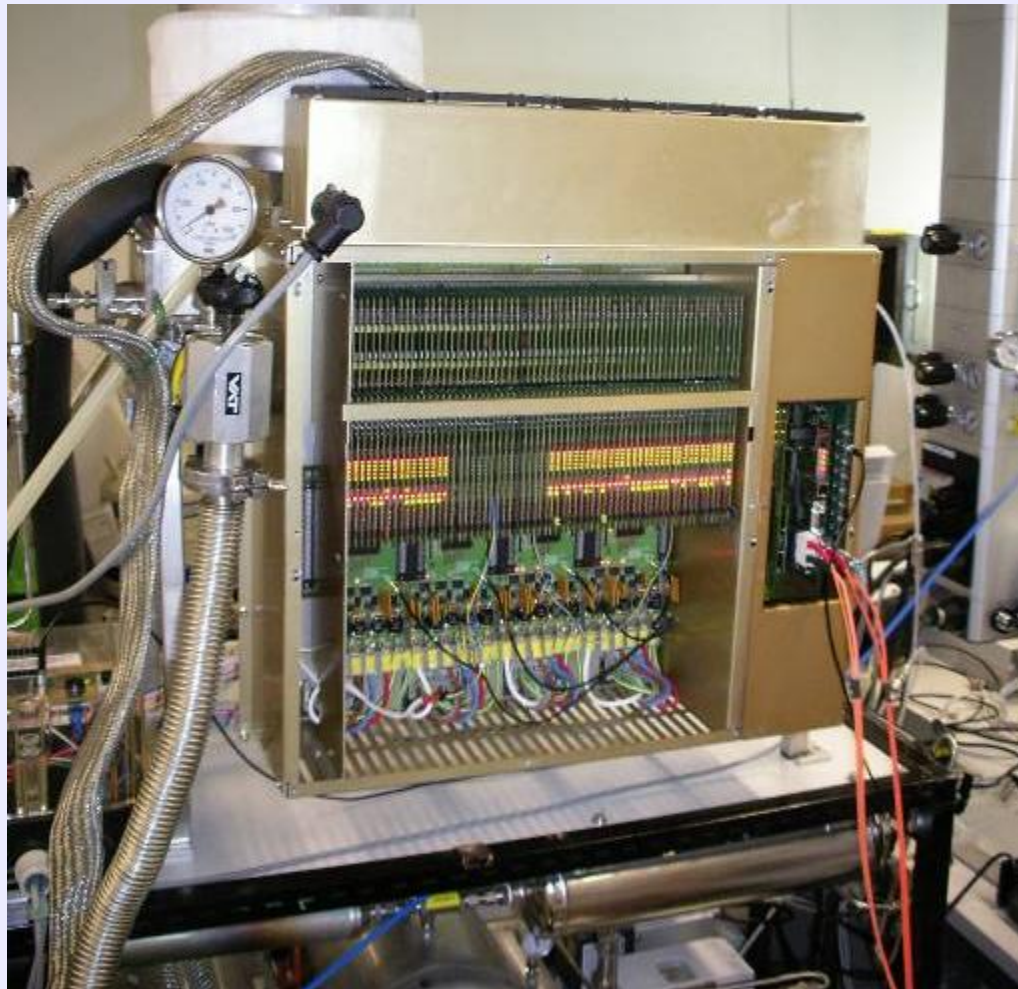
Pile-Up Detection



Fast and Slow PIN-Diodes

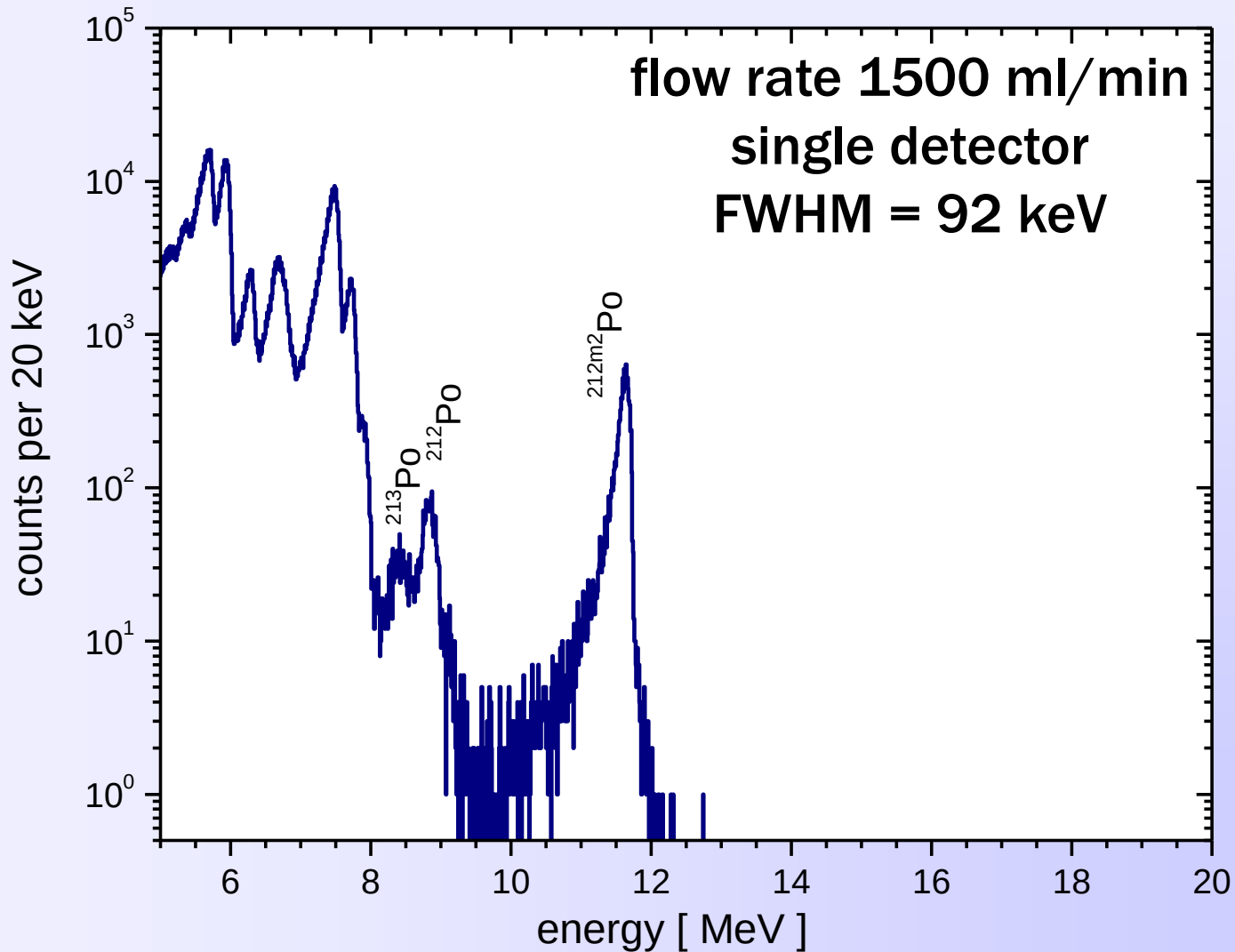


pureCOLD mounted for on-line experiments



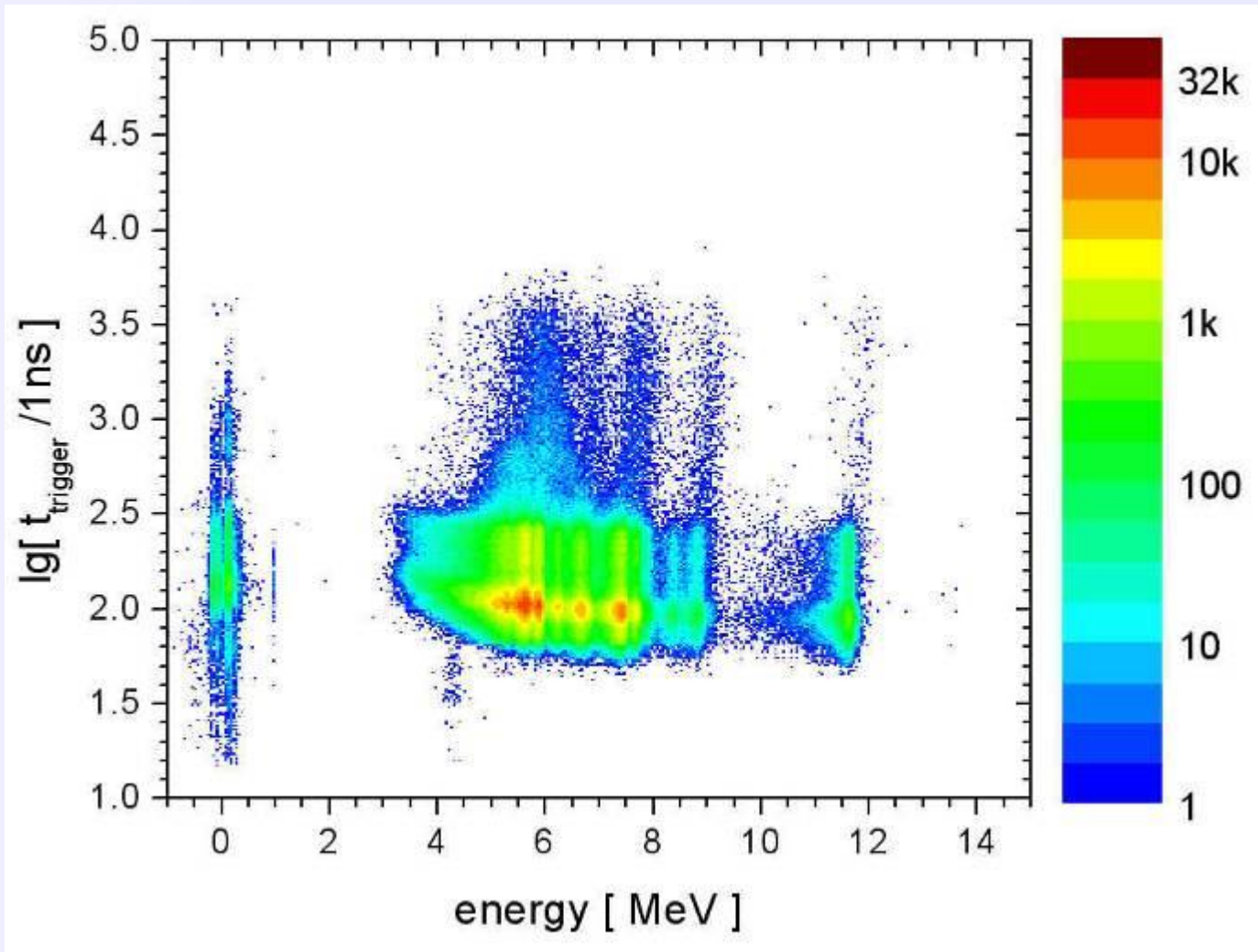
Dubna 2011

$^{244}\text{Pu} + ^{48}\text{Ca}$

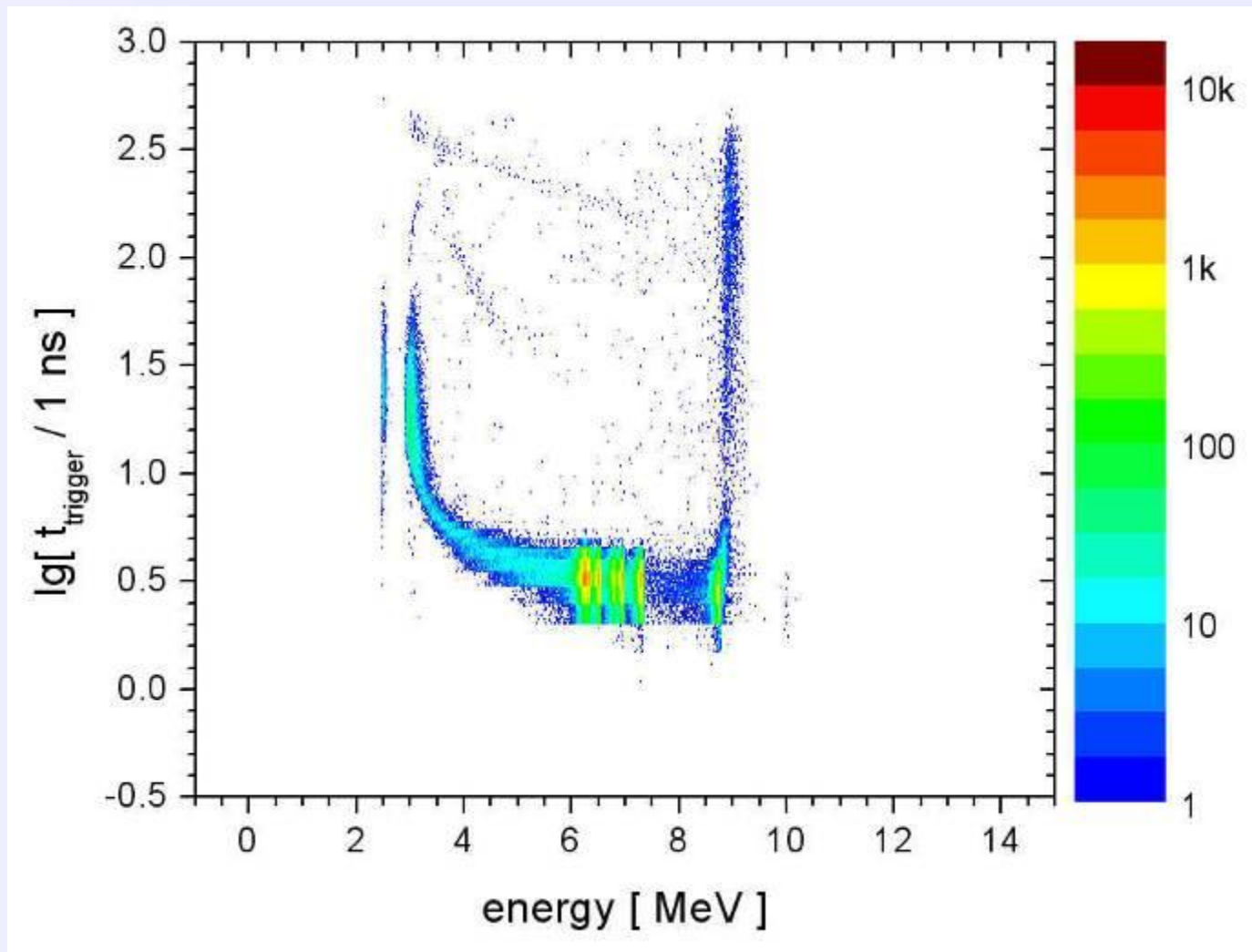


Dubna 2011

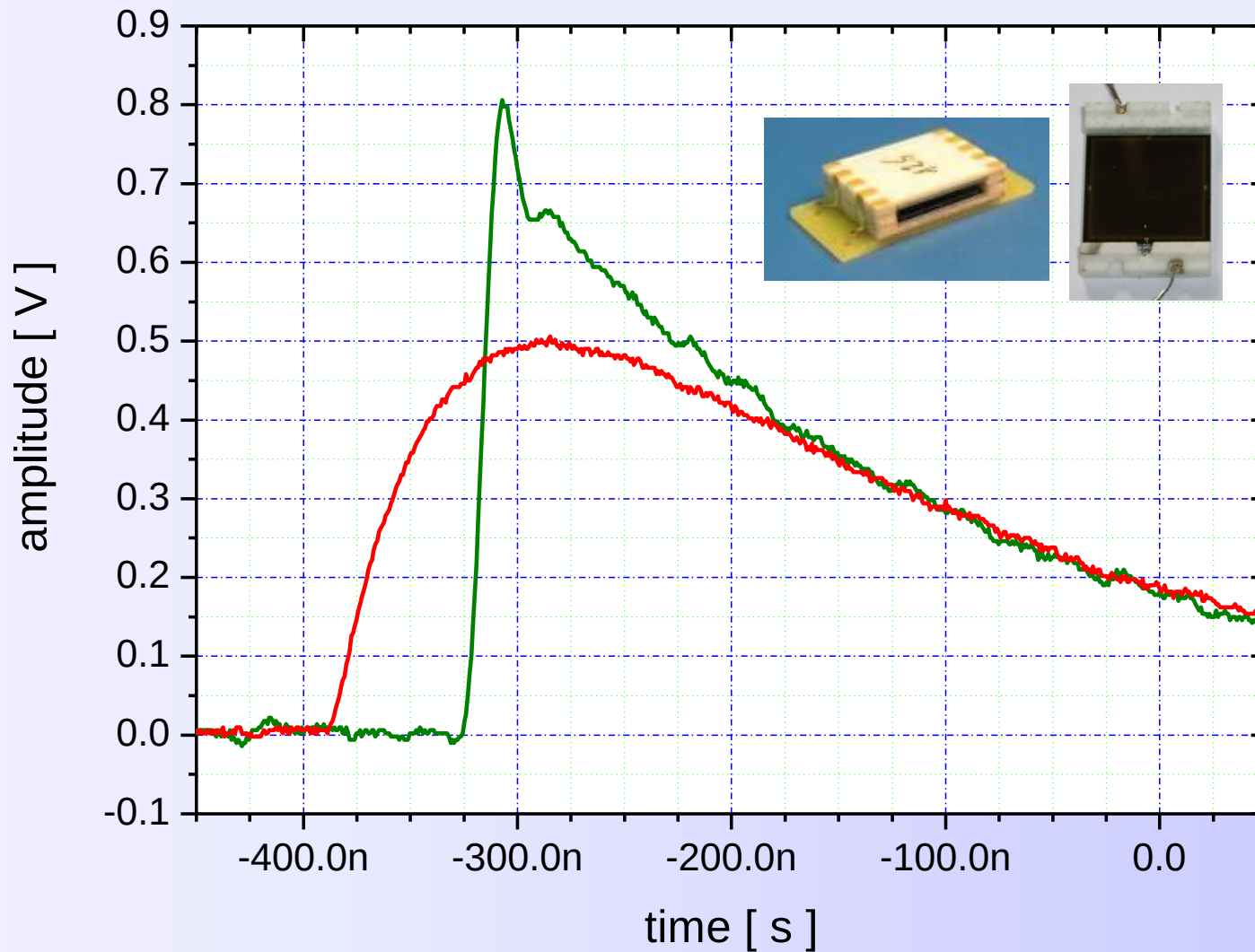
$^{244}\text{Pu} + ^{48}\text{Ca}$



Test at PSI



Fast and slow Signals



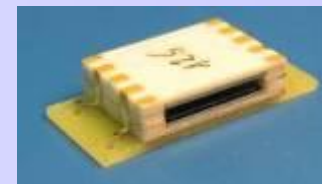
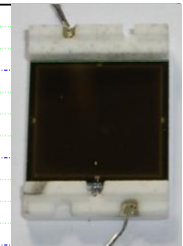
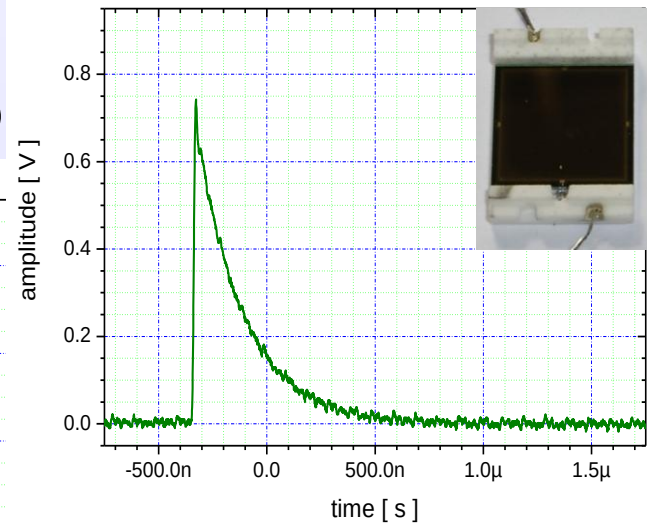
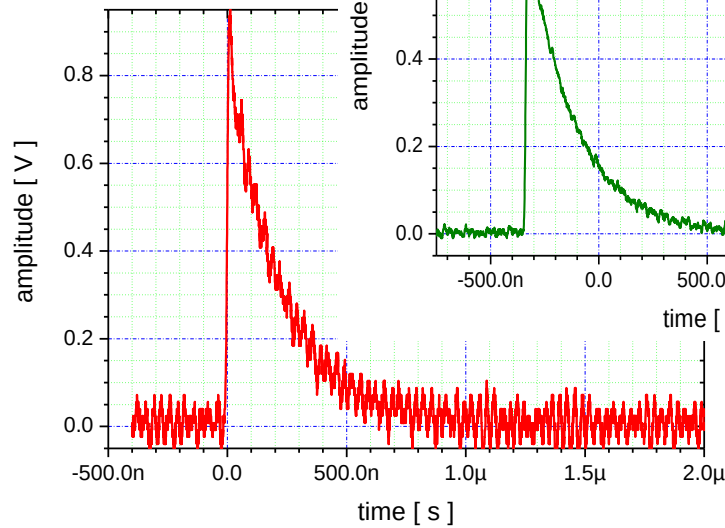
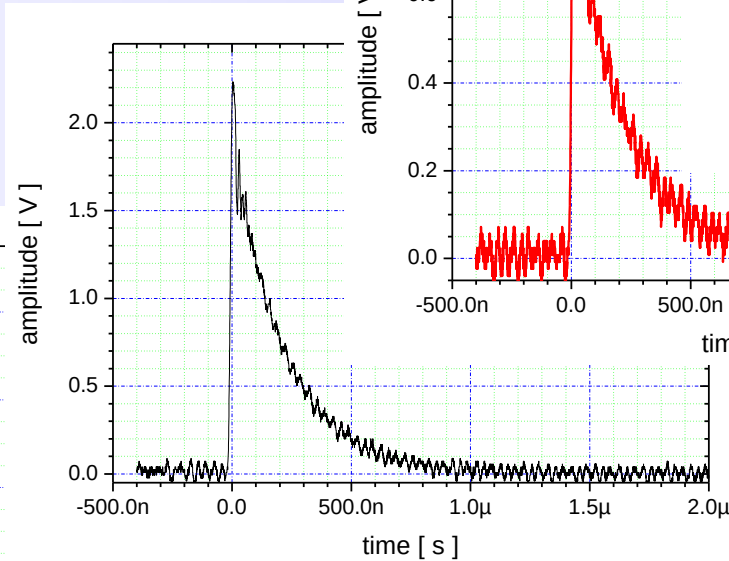
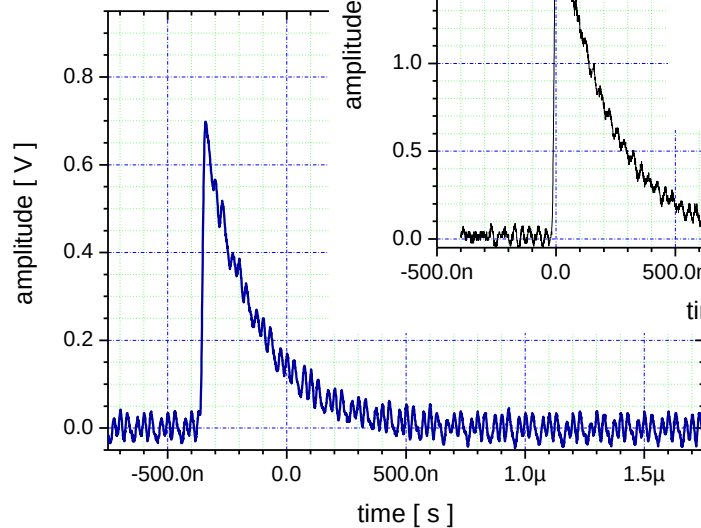
Signal Noise

PSI COLD test setup

Dubna COLD

Dubna COLD

PSI COLD



Summary

- good spectroscopic behavior in test experiments
 - *4 μ s minimal time between events*
 - *FWHM ~ 40 keV*
 - *pile-up identification about 90%*
- spectroscopic behavior in on-line use
 - *pureCOLD is ready for on-line experiments*
 - *FWHM ~ 90 keV (single detector)*
 - *FWHM ~ 120 keV (all COLD detectors)*

Outlook

■ Tuning interconnections

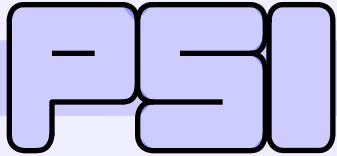
- *safe transfer protocol FE – MB – GigaSTaR*
- *use full speed of GigaStaR 1.32 GBit/sec*
max. through put 1.85 MEvents/sec

■ Improvements of FE hardware

- *max. full range of fast timing amplifier 15 MeV*
- *noise reduction of analog signals*
- *rise time problem of PIN-diodes*

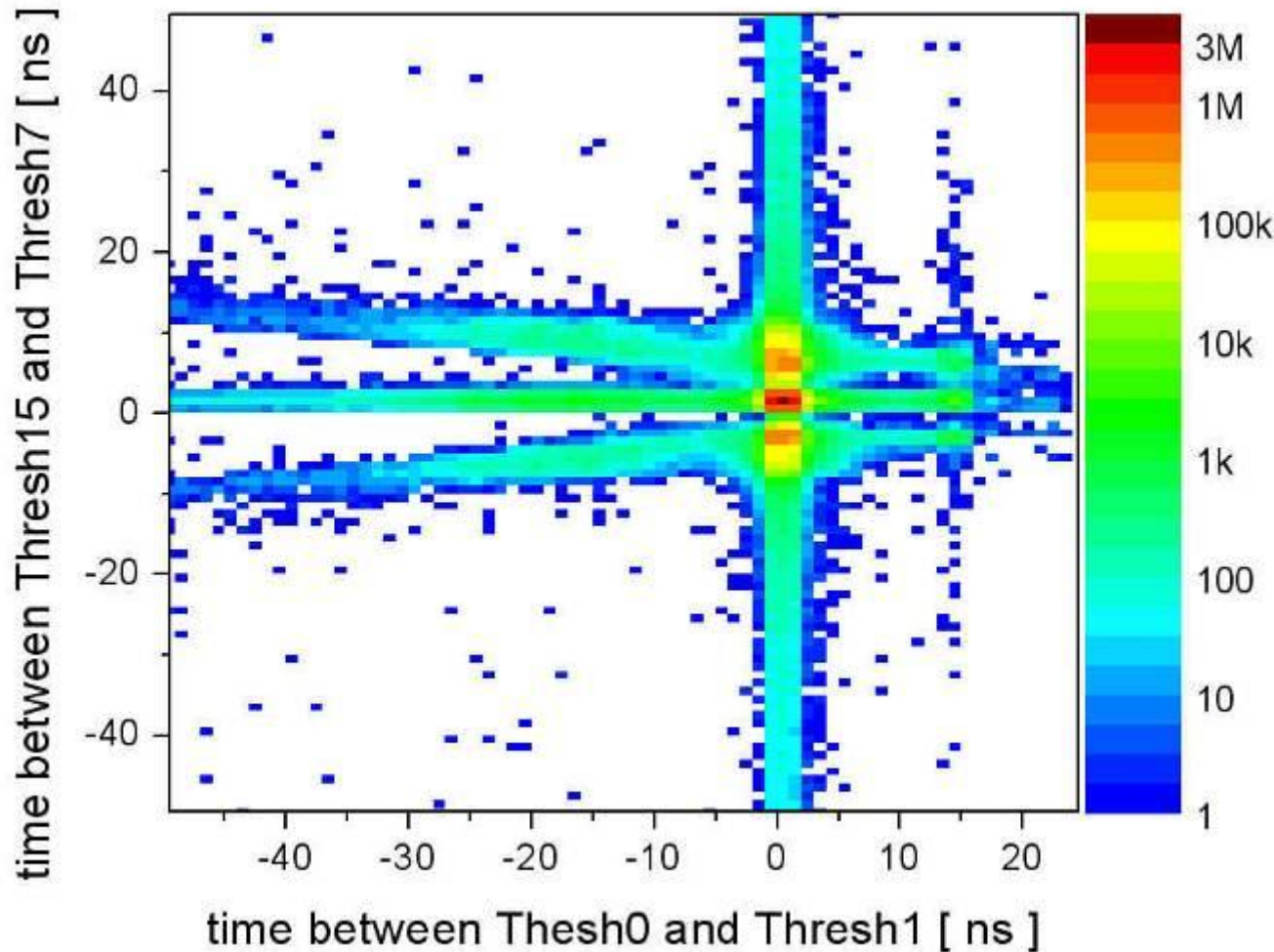
■ Improvements of FE FPGA-configurations

- *leading edge detection of threshold passing*
- *fast counter implementation for threshold time stamp*



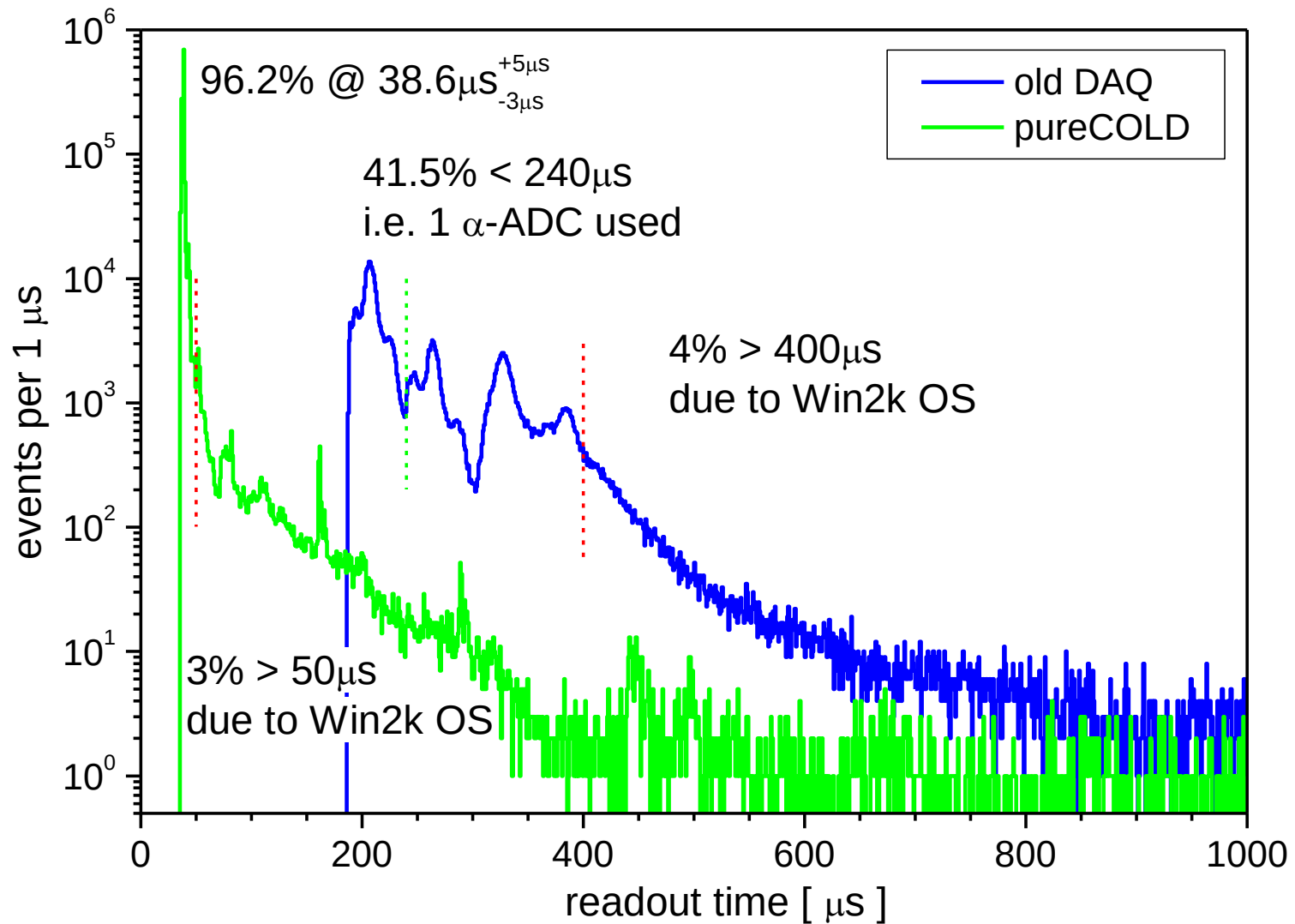
**Thank you
for
your attention**

Time between identical Threshold Voltages

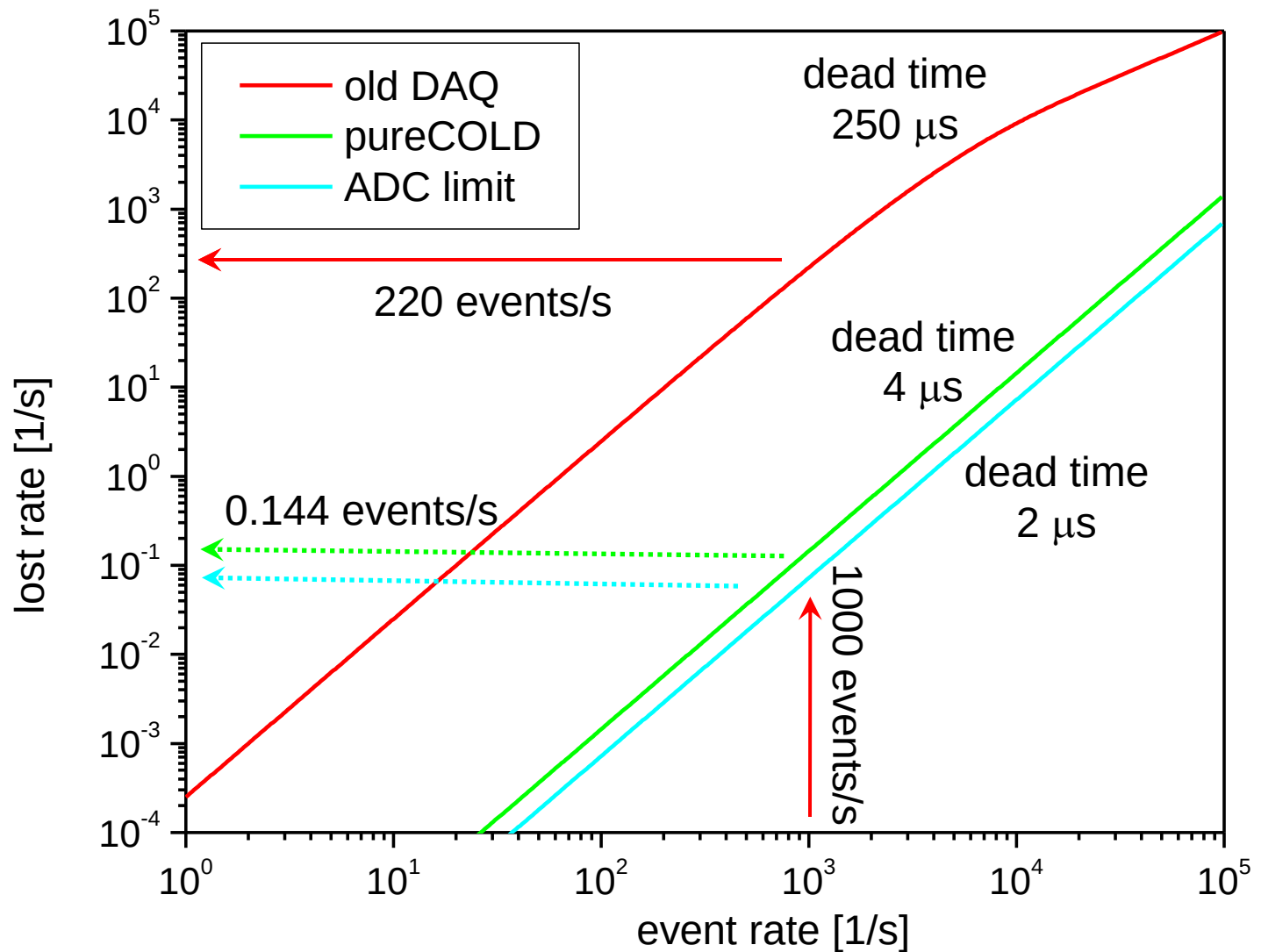


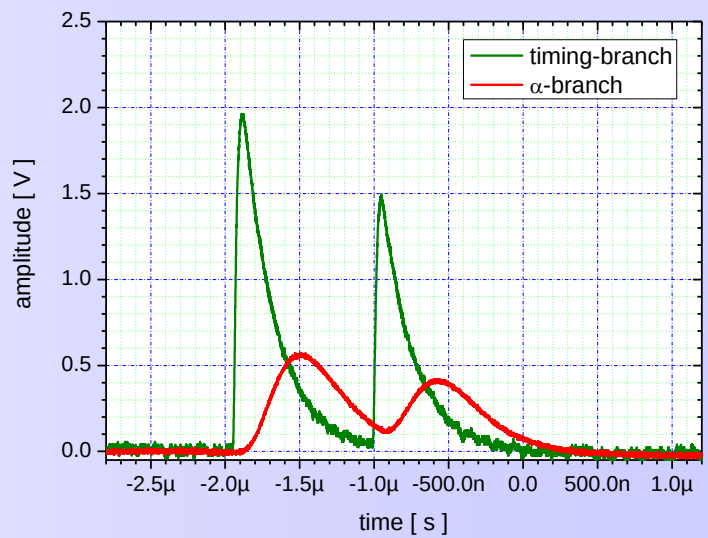
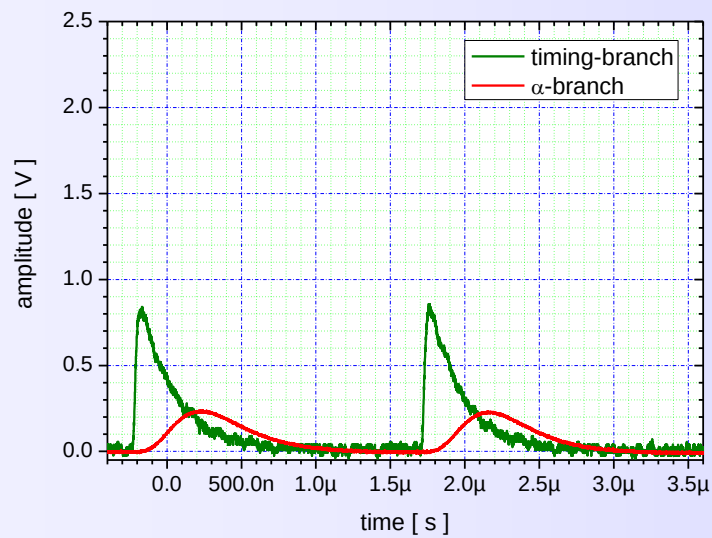
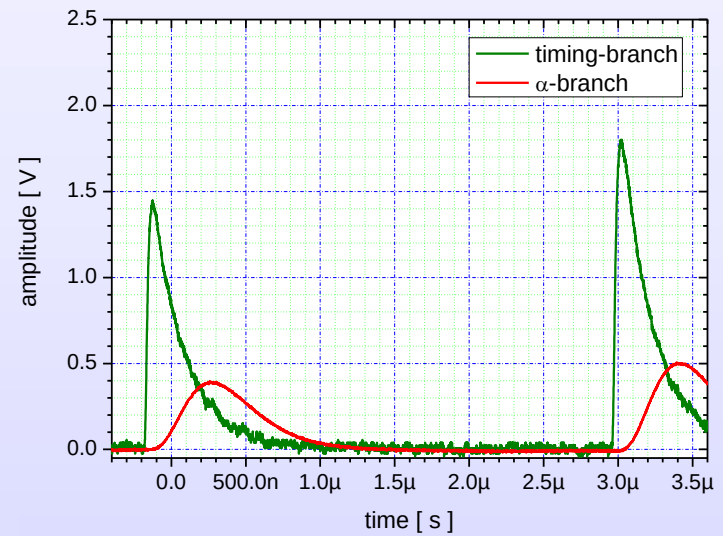
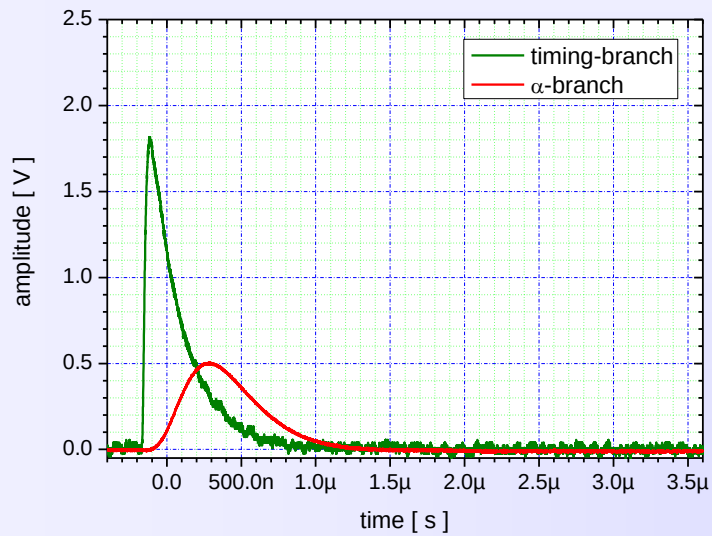
Th#	Level [mV]
15	1000.00
11	2401.96
13	2196.08
12	2000.00
11	1500.00
10	598.04
9	401.96
8	196.08
7	1000.00
6	89.04
5	78.43
4	49.02
3	29.91
2	20.15
1	9.77
0	9.77

Readout Time Spectrum

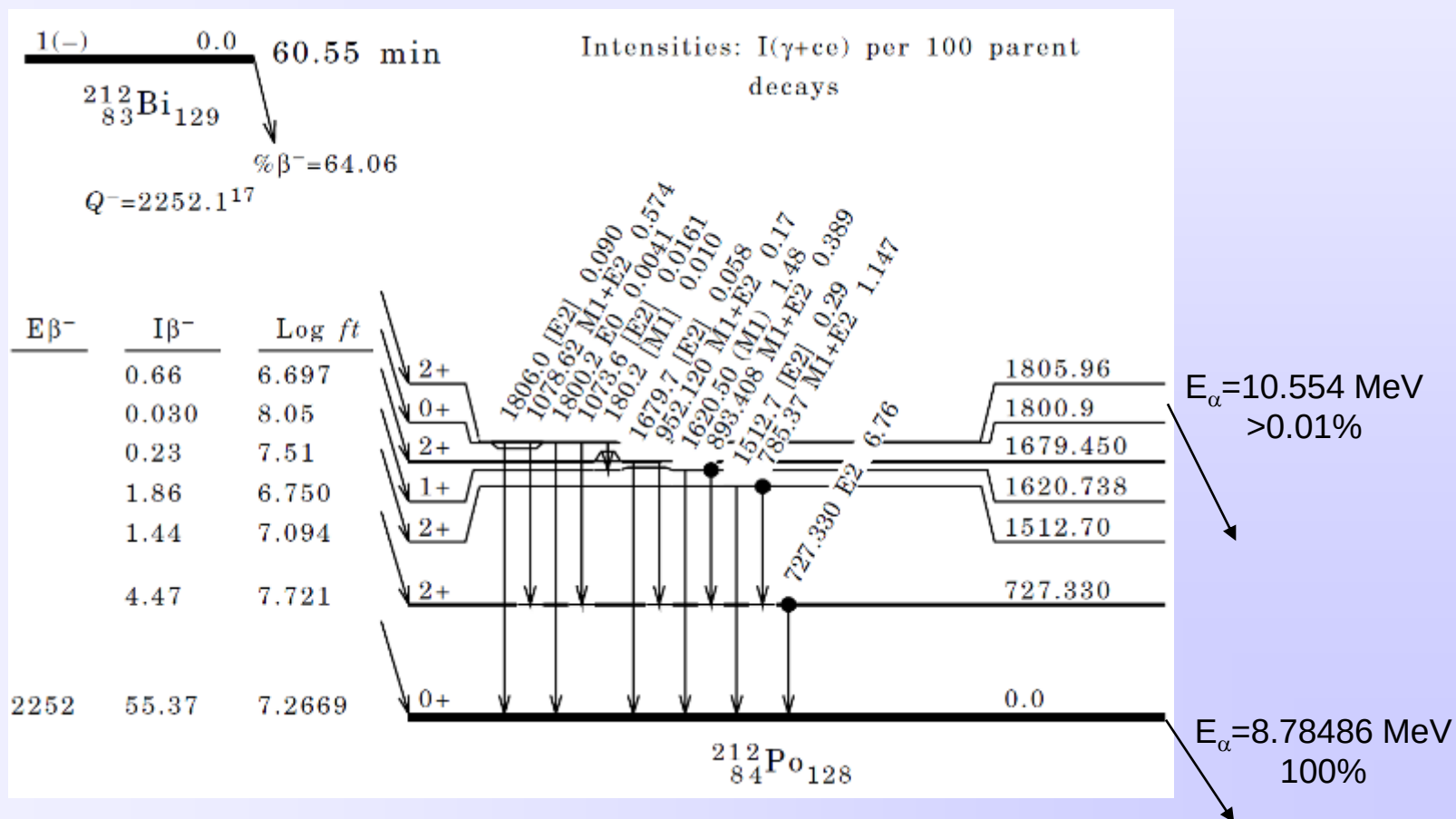


Event Lost Rate





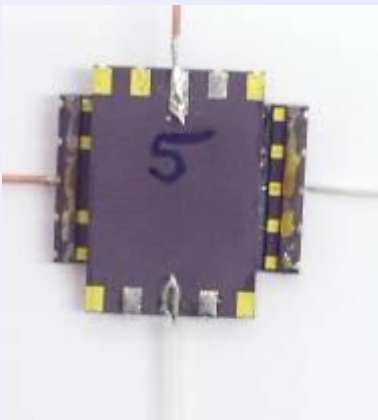
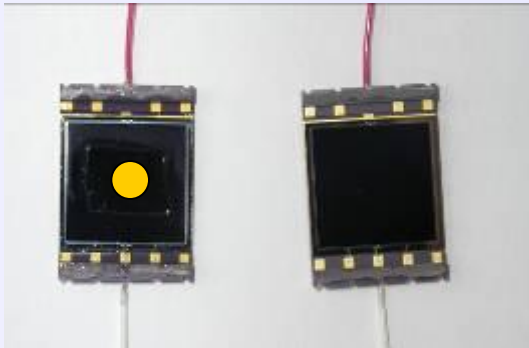
Decay schema of ^{212}Bi



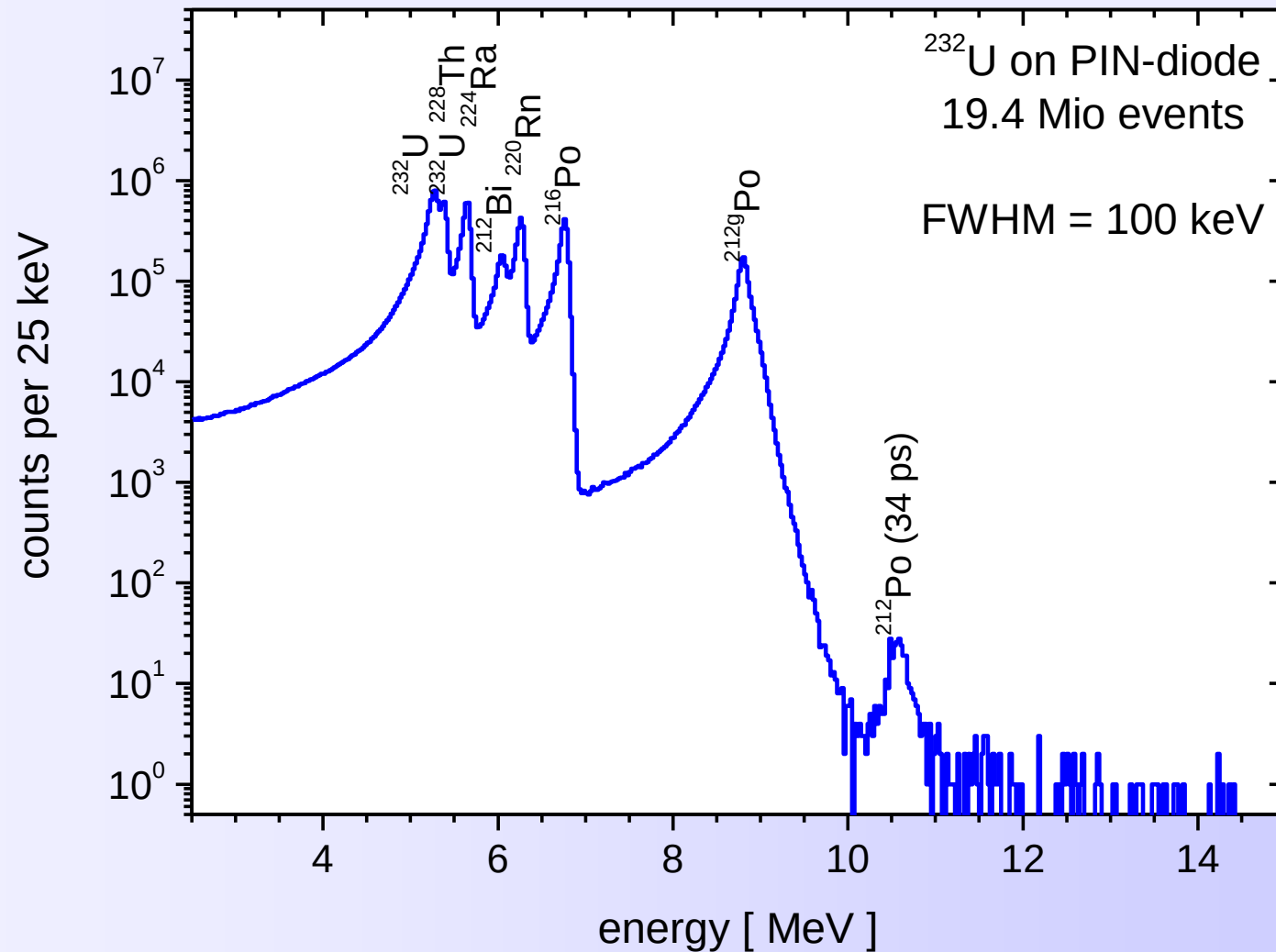
Event Structure

dword	31(MSB)	(LSB)0
1	Event state (16bit)	Event type (8bit) FE no (8 bit)
2	Alpha ADC conv. time (16bit)	Alpha ADC (16bit)
3	Fiss ADC conv. time (16bit)	Fiss ADC (16bit)
4	Thresh. Time 1 (16bit)	Thresh. Time 0 (16bit)
5	Thresh. Time 3 (16bit)	Thresh. Time 2 (16bit)
6	Thresh. Time 5 (16bit)	Thresh. Time 4 (16bit)
7	Thresh. Time 7 (16bit)	Thresh. Time 6 (16bit)
8	Thresh. Time 9 (16bit)	Thresh. Time 8 (16bit)
9	Thresh. Time 11 (16bit)	Thresh. Time 10 (16bit)
10	Thresh. Time 13 (16bit)	Thresh. Time 12 (16bit)
11	Thresh. Time 15 (16bit)	Thresh. Time 14 (16bit)
18	Beam counter (32bit)	
19	I/O state (16bit)	Beam counter (16bit)
20	Time stamp (32bit)	
21	nn (8bit) ss (8bit)	Time stamp (16bit)
22	yy (8bit) mm (8bit) dd (8bit) hh (8bit)	

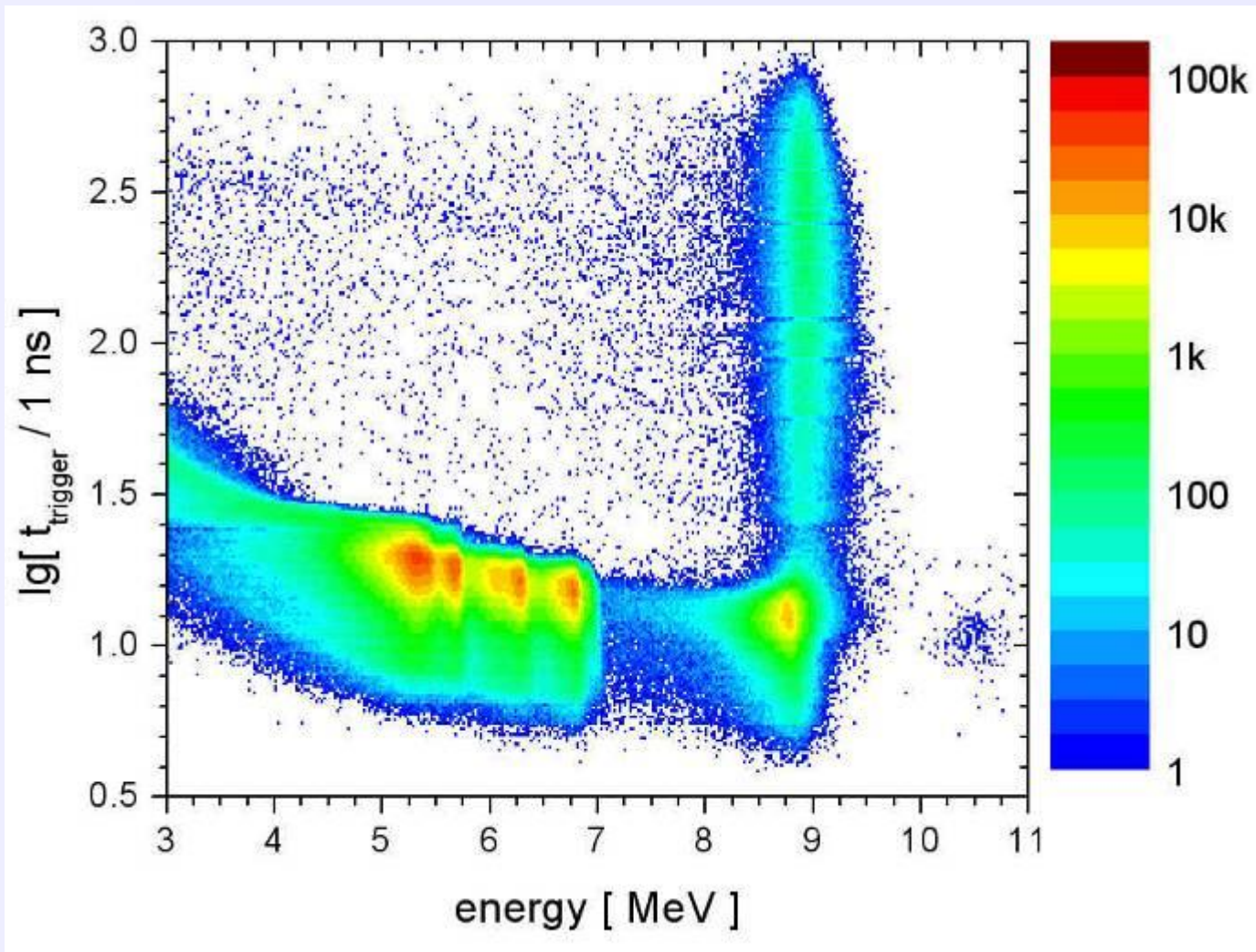
First measurements



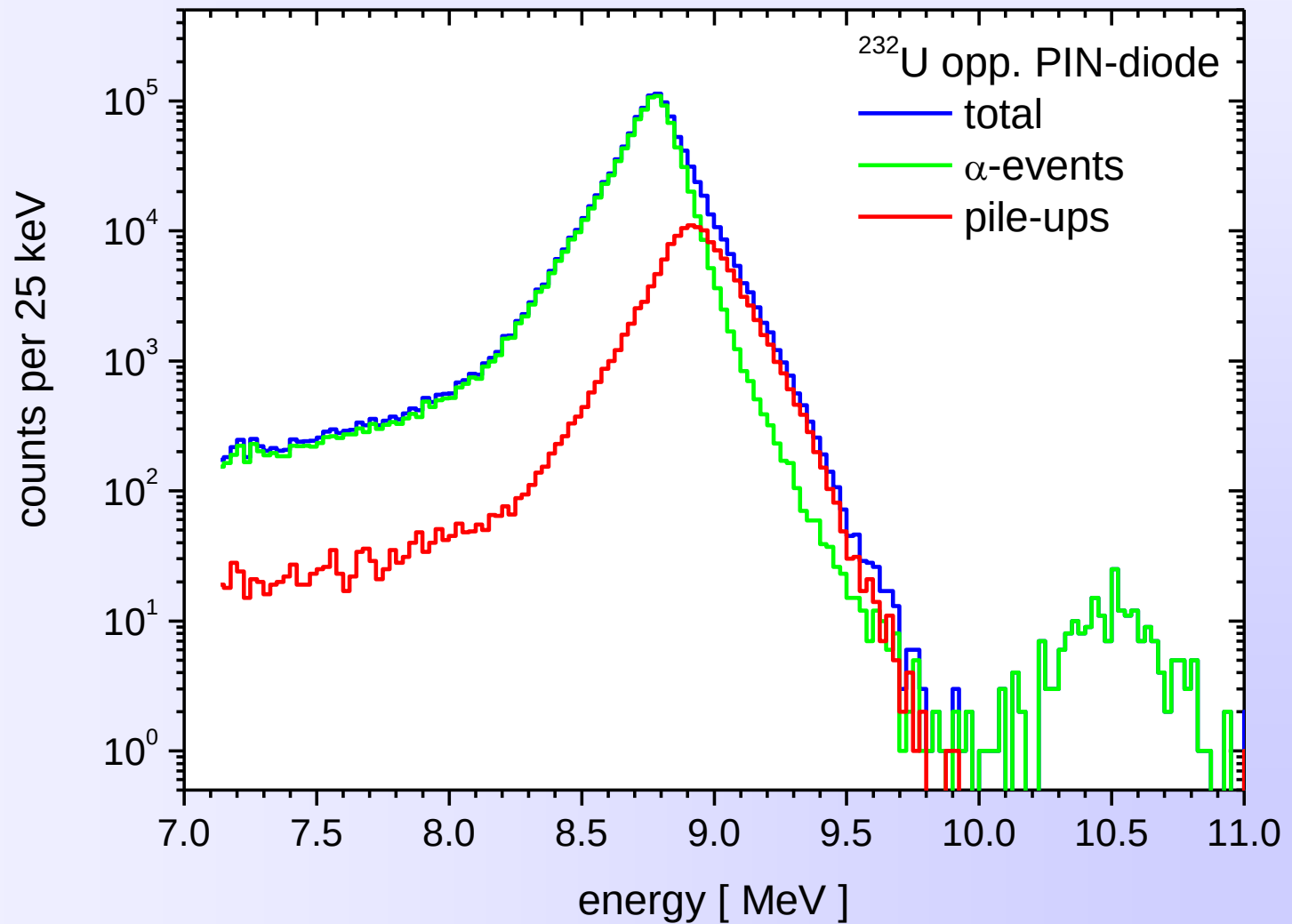
^{232}U α -Spectrum



^{232}U Threshold-Time vs. α -Energy

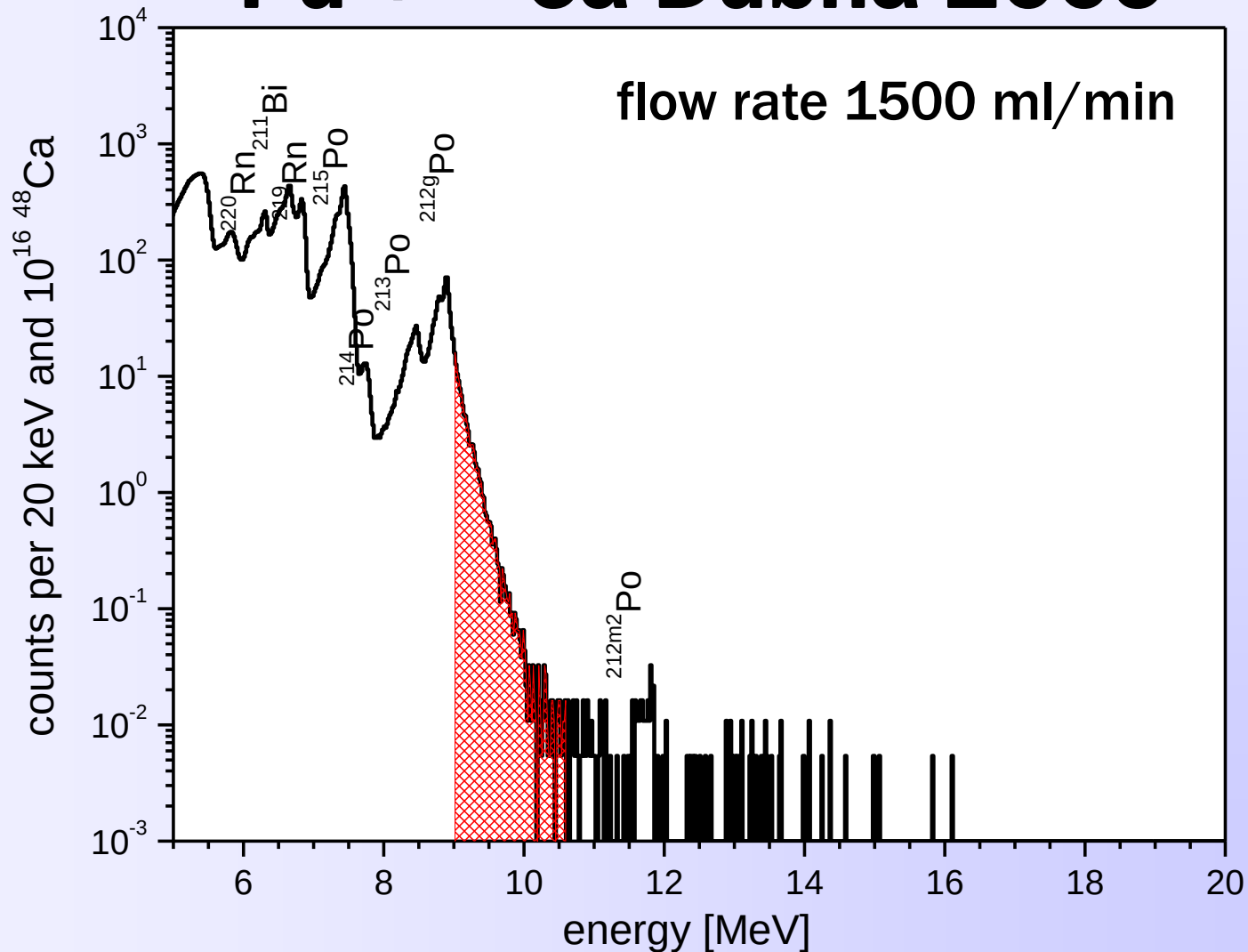


Pile-Up Detection



β - α Pile-up Spectrum

$^{242}\text{Pu} + ^{48}\text{Ca}$ Dubna 2009



α - α Pile-up Spectrum

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